

Dual N-Channel 20-V (D-S) MOSFET

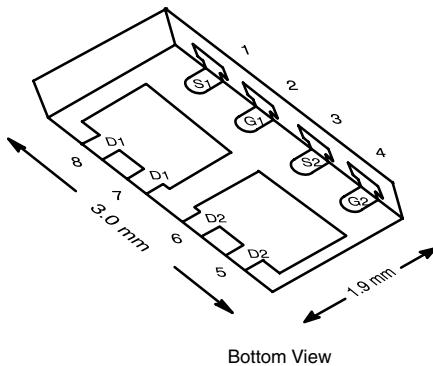
PRODUCT SUMMARY			
V_{DS} (V)	r_{DS(on)} (Ω)	I_D (A)^a	Q_g (Typ)
20	0.039 @ V _{GS} = 4.5 V	6	6 nC
	0.045 @ V _{GS} = 2.5 V	6	
	0.055 @ V _{GS} = 1.8 V	6	

FEATURES

- TrenchFET® Power MOSFET
- New Thermally Enhanced PowerPAK® ChipFET® Package
 - Small Footprint Area
 - Low On-Resistance
 - Thin 0.8mm Profile



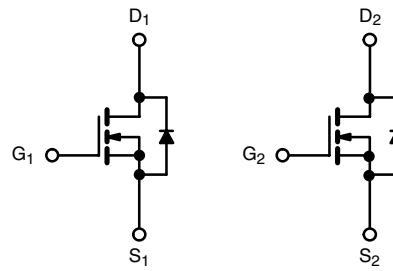
PowerPAK® ChipFET® Dual



Marking Code
CA XXX
Lot Traceability and Date Code
Part # Code

APPLICATIONS

- Load Switch for Portable Applications
- DC-DC Point-of-Load



N-Channel MOSFET

N-Channel MOSFET

Ordering Information: Si5938DU-T1-E3

ABSOLUTE MAXIMUM RATINGS (T_A = 25°C UNLESS OTHERWISE NOTED)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	20	V
Gate-Source Voltage	V _{GS}	±8	
Continuous Drain Current (T _J = 150°C)	I _D	6 ^a	A
		6 ^a	
		7.2 ^{b, c}	
		5.8 ^{b, c}	
Pulsed Drain Current	I _{DM}	20	
Continuous Source-Drain Diode Current	I _S	6.9	
		1.9 ^{b, c}	
Maximum Power Dissipation	P _D	8.3	W
		5.3	
		2.3 ^{b, c}	
		1.5 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	-55 to 150	°C
Soldering Recommendations (Peak Temperature) ^{d, e}		260	

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, f}	t ≤ 5 sec	R _{thJA}	45	°C/W
Maximum Junction-to-Case (Drain)	Steady State	R _{thJC}	12	
Notes:			15	

a. Package limited.

b. Surface Mounted on 1" x 1" FR4 Board.

c. t = 5 sec

d. See Solder Profile (<http://www.vishay.com/doc?73257>). The PowerPAK ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.

e. Rework Conditions: manual soldering with a soldering iron is not recommended for leadless components.

f. Maximum under steady state conditions is 105 °C/W.

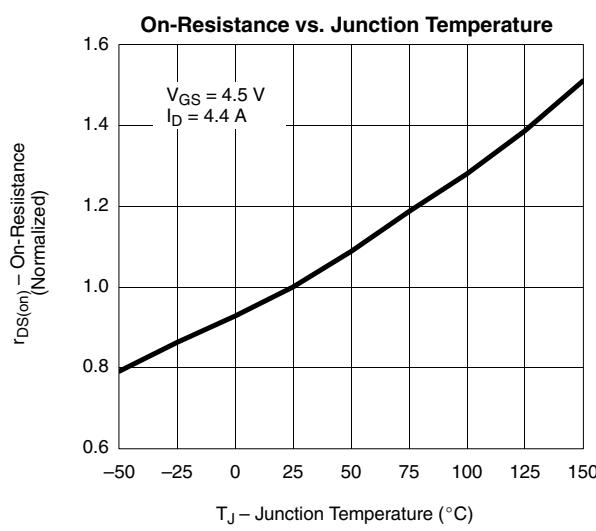
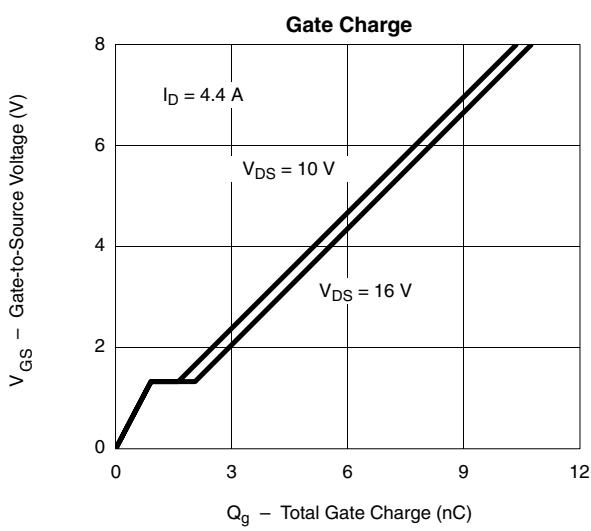
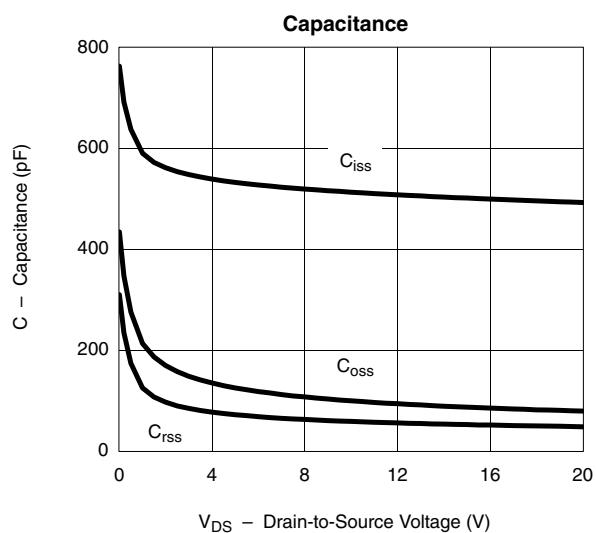
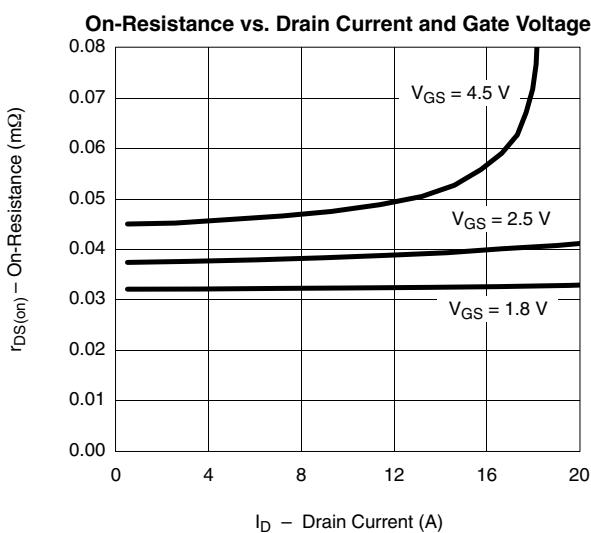
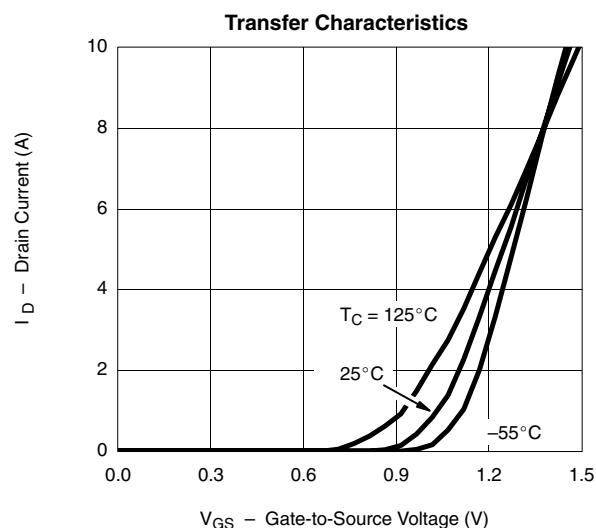
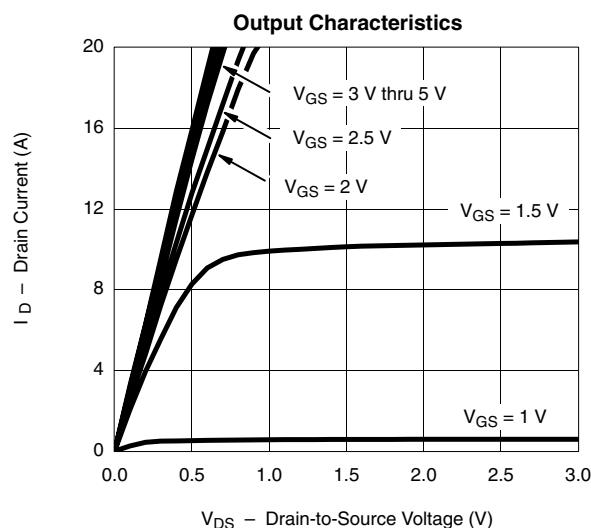
SPECIFICATIONS ($T_J = 25^\circ\text{C}$ UNLESS OTHERWISE NOTED)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$	17.4	-2.6		$\text{mV}/^\circ\text{C}$
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$					
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	0.4		1.0	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$			± 100	ns
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$		-1		
		$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$		-10		μA
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} \leq 5 \text{ V}, V_{GS} = 4.5 \text{ V}$	-20			A
Drain-Source On-State Resistance ^a	$r_{DS(\text{on})}$	$V_{GS} = 4.5 \text{ V}, I_D = 4.4 \text{ A}$		0.032	0.039	Ω
		$V_{GS} = 2.5 \text{ V}, I_D = 4.1 \text{ A}$		0.037	0.045	
		$V_{GS} = 1.8 \text{ V}, I_D = 1.8 \text{ A}$		0.0455	0.055	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 10 \text{ V}, I_D = 4.4 \text{ A}$		22		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = 10 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		520		pF
Output Capacitance	C_{oss}			100		
Reverse Transfer Capacitance	C_{rss}			60		
Total Gate Charge	Q_g	$V_{DS} = 10 \text{ V}, V_{GS} = 8 \text{ V}, I_D = 4.4 \text{ A}$	10.5	16		nC
Gate-Source Charge	Q_{gs}	$V_{DS} = 10 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 4.4 \text{ A}$	6	9		
Gate-Drain Charge	Q_{gd}		0.91			
Gate Resistance	R_g		0.7			
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = 10 \text{ V}, R_L = 2.8 \Omega$ $I_D \approx 3.6 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$	1.9			Ω
Rise Time	t_r		20	30		
Turn-Off Delay Time	$t_{d(\text{off})}$		65	100		
Fall Time	t_f		40	60		
Turn-On Delay Time	$t_{d(\text{on})}$		10	15		
Rise Time	t_r		5	10		
Turn-Off Delay Time	$t_{d(\text{off})}$	$V_{DD} = 10 \text{ V}, R_L = 2.8 \Omega$ $I_D \approx 3.6 \text{ A}, V_{GEN} = 8 \text{ V}, R_g = 1 \Omega$	12	20		ns
Fall Time	t_f		26	40		
			8	15		
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$			14.8	A
Pulse Diode Forward Current	I_{SM}				20	
Body Diode Voltage	V_{SD}	$I_S = 1.2 \text{ A}, V_{GS} = 0 \text{ V}$	0.8	1.2		V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 1.2 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$	45	70		ns
Body Diode Reverse Recovery Charge	Q_{rr}		21	32		nC
Reverse Recovery Fall Time	t_a		29			ns
Reverse Recovery Rise Time	t_b		16			

Notes

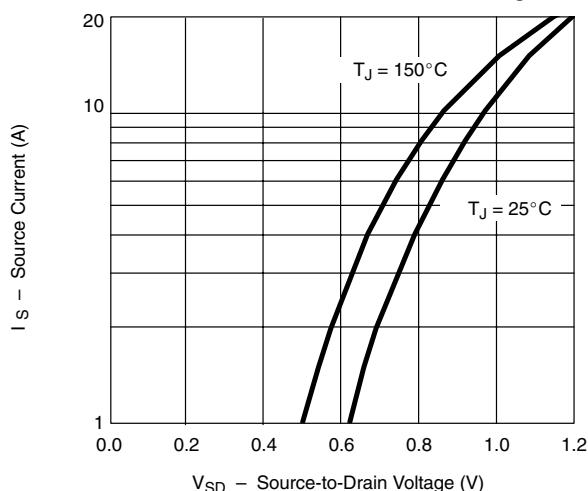
- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

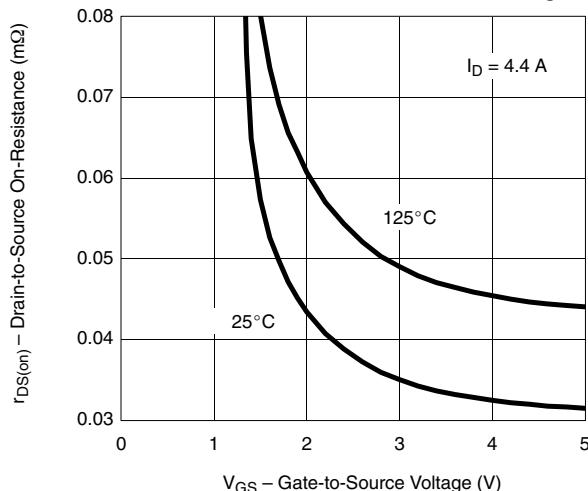
TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)


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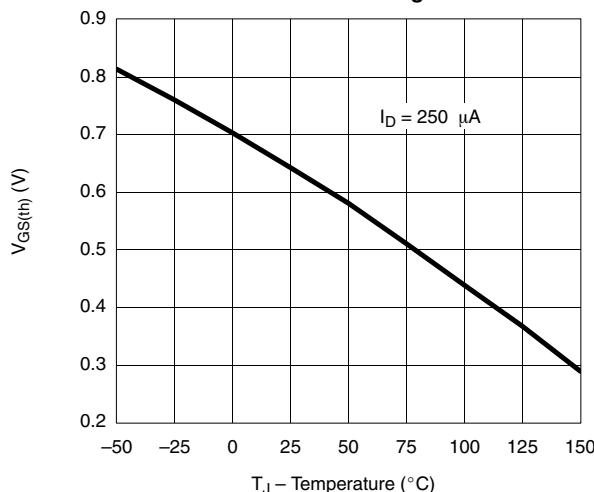
Source-Drain Diode Forward Voltage



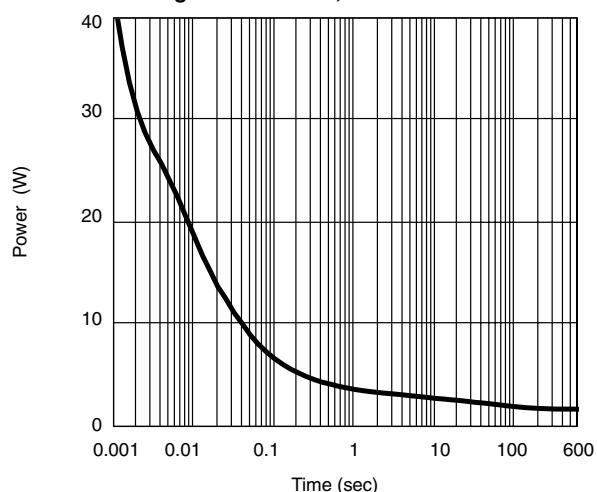
On-Resistance vs. Gate-to-Source Voltage



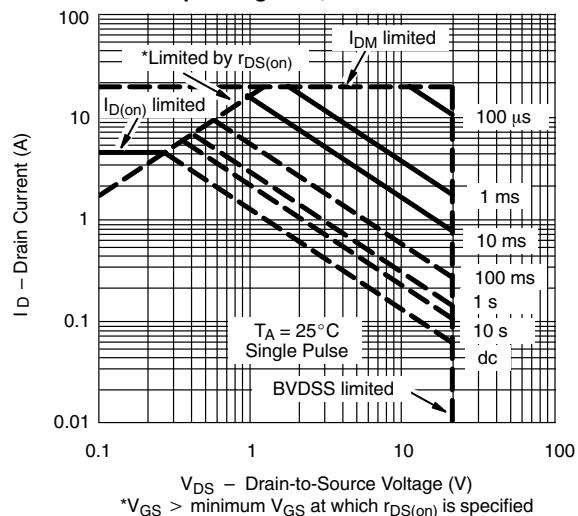
Threshold Voltage



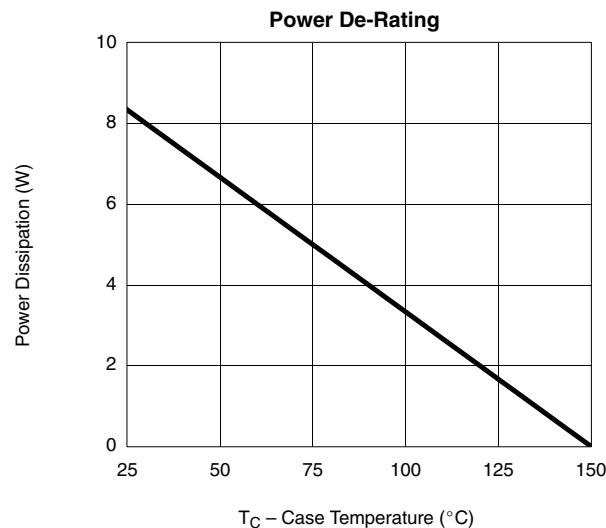
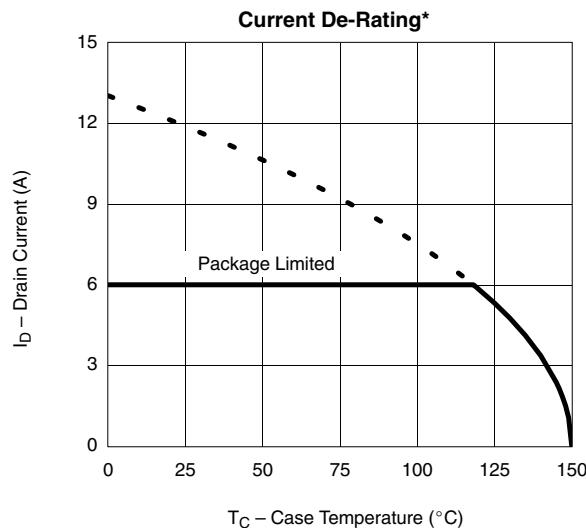
Single Pulse Power, Junction-to-Ambient



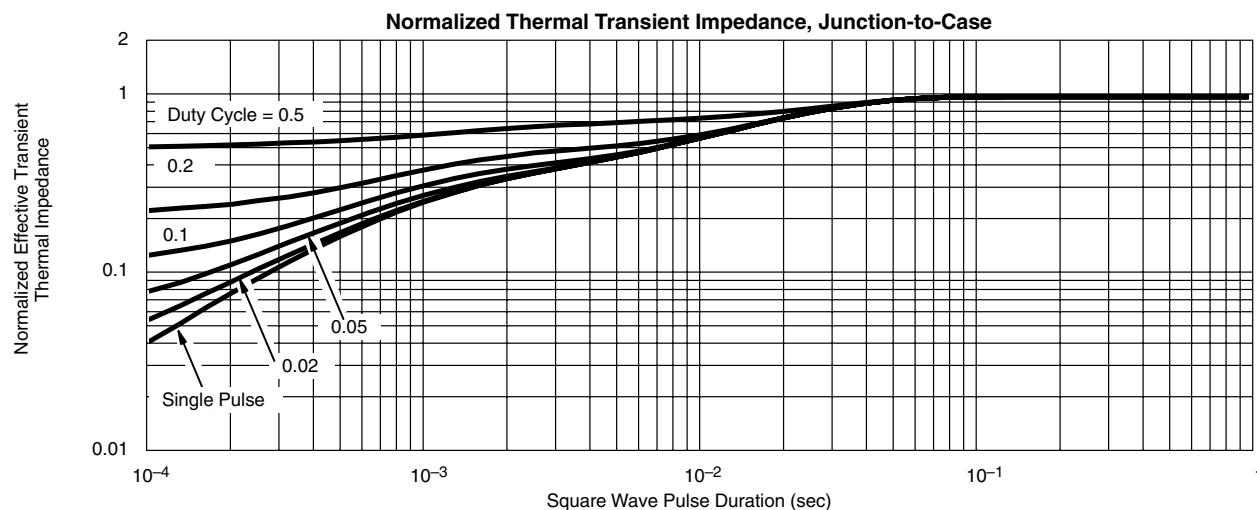
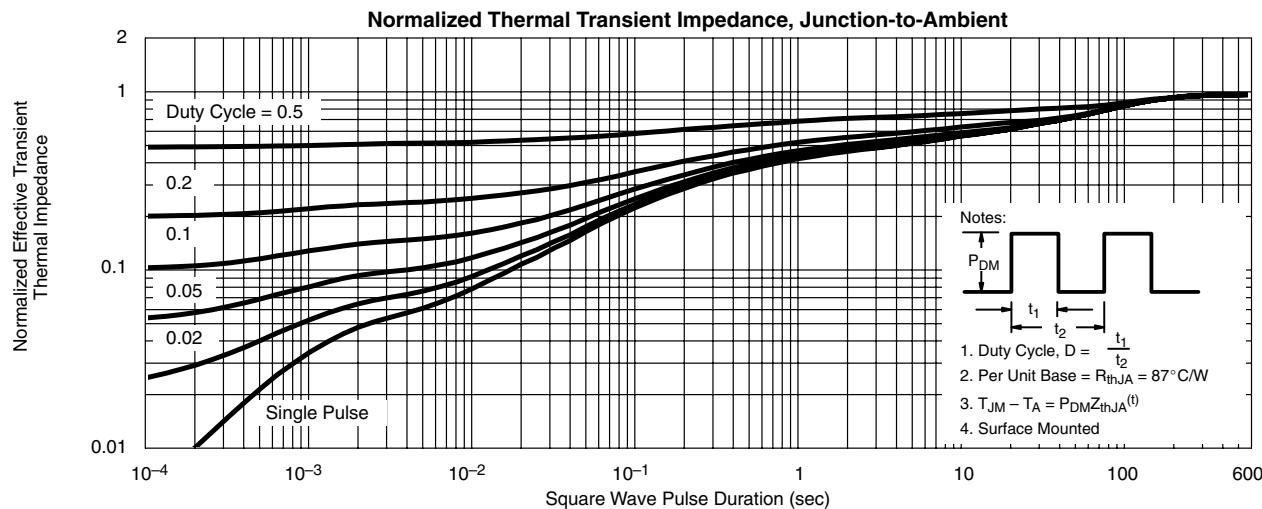
Safe Operating Area, Junction-to-Ambient



$*V_{GS} > \text{minimum } V_{GS} \text{ at which } r_{DS(on)} \text{ is specified}$

TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)


*The power dissipation P_D is based on $T_{J(max)} = 150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS (25°C UNLESS NOTED)

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